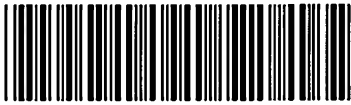


**Search Notes**

Application/Control No.

10/626,736

Examiner

Vuthe Siek

Applicant(s)/Patent under  
Reexamination

LIN, CHE-SHENG

Art Unit

2825

**SEARCHED**

| Class | Subclass  | Date     | Examiner |
|-------|-----------|----------|----------|
| 716   | 1,3,18    | 3/1/2005 | VS       |
| 710   | 13-19     | 3/1/2005 | VS       |
| 710   | 22-24,26  | 3/1/2005 | VS       |
| 710   | 35-36,39  | 3/1/2005 | VS       |
| 710   | 51,120    | 3/1/2005 | VS       |
| 365   | 189.01-05 | 3/1/2005 | VS       |
| 711   | 111-112   | 3/1/2005 | VS       |
| 358   | 1.15-1.17 | 3/1/2005 | VS       |
| 370   | 412,419   | 3/1/2005 | VS       |
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**INTERFERENCE SEARCHED**

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|                           | DATE     | EXMR |
|---------------------------|----------|------|
| EAST all databases & IEEE | 3/1/2005 | VS   |
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